

Final datasheet

XHP™2 module with CoolSiC™ Trench MOSFET

Features

- Electrical features
 - $V_{DS} = 3300\text{ V}$
 - $I_{DN} = 500\text{ A} / I_{DRM} = 1000\text{ A}$
 - $T_{vj,op} = 175^{\circ}\text{C}$
 - Low switching losses
 - High current density
 - Low inductive design
- Mechanical features
 - High power density
 - Package with CTI > 600
 - High creepage and clearance distances
 - AlSiC base plate for increased thermal cycling capability
 - AlN substrate with low thermal resistance



Potential applications

- Traction drives
- High-power converters
- High-frequency switching application

Product validation

- Qualified for industrial applications according to the relevant tests of IEC 60747, 60749 and 60068

Description

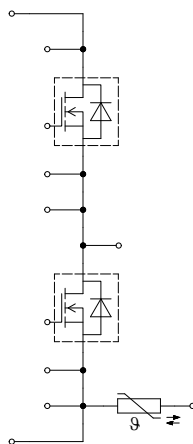


Table of contents

	Description	1
	Features	1
	Potential applications	1
	Product validation	1
	Table of contents	2
1	Package	3
2	MOSFET	3
3	Body diode (MOSFET)	6
4	NTC-Thermistor	6
5	Characteristics diagrams	7
6	Circuit diagram	13
7	Package outlines	14
8	Module label code	15
	Revision history	16
	Disclaimer	17

1 Package

Table 1 Insulation coordination

Parameter	Symbol	Note or test condition	Values	Unit
Isolation test voltage	V_{ISOL}	RMS, $f = 50 \text{ Hz}$, $t = 1 \text{ min}$	6.0	kV
Partial discharge extinction voltage	V_{isol}	RMS, $f = 50 \text{ Hz}$, $Q_{PD} \leq 10 \text{ pC}$	2.6	kV
DC stability	$V_{CE(D)}$	$T_{vj} = 25 \text{ °C}$, 100 Fit	2100	V
Material of module baseplate			AlSiC	
Creepage distance	$d_{Creep \text{ nom}}$	terminal to baseplate, nom.	40.0	mm
Creepage distance	$d_{Creep \text{ nom}}$	terminal to terminal, nom.	34.0	mm
Clearance	$d_{Clear \text{ nom}}$	terminal to baseplate, nom.	31.0	mm
Clearance	$d_{Clear \text{ nom}}$	terminal to terminal, nom.	8.0	mm
Comparative tracking index	CTI		> 600	

Table 2 Characteristic values

Parameter	Symbol	Note or test condition		Values			Unit
				Min.	Typ.	Max.	
Stray inductance module	L_{sCE}				10		nH
Module lead resistance, terminals - chip	$R_{CC'+EE'}$	$T_C = 25\text{ }^{\circ}\text{C}$, per switch			0.43		mΩ
Storage temperature	T_{stg}			-40		150	°C
Maximum baseplate operation temperature	T_{BPmax}					150	°C
Mounting torque for module mounting	M	- Mounting according to valid application note	M6, Screw	4.25		5.75	Nm
Terminal connection torque	M	- Mounting according to valid application note	M3, Screw	0.9		1.1	Nm
			M8, Screw	8		10	
Weight	G				720		g

2 MOSFET

Table 3 Maximum rated values

Parameter	Symbol	Note or test condition	Values	Unit
Drain-source voltage	V_{DSS}	$T_{vj} = 25 \text{ °C}$	3300	V
Implemented drain current	I_{DN}		500	A
Continuous DC drain current	I_{DDC}	$T_{vj} = 175 \text{ °C}$, $V_{GS} = 15 \text{ V}$ $T_C = 35 \text{ °C}$	500	A

(table continues...)

Table 3 (continued) Maximum rated values

Parameter	Symbol	Note or test condition	Values	Unit
Repetitive peak drain current	I_{DRM}	verified by design, t_p limited by $T_{vj\text{max}}$	1000	A
Gate-source voltage, max. transient voltage	V_{GS}	$D < 0.01$	-10/23	V
Gate-source voltage, max. static voltage	V_{GS}		-7/20	V

Table 4 Recommended values

Parameter	Symbol	Note or test condition	Values	Unit
On-state gate voltage	$V_{\text{GS(on)}}$		15...18	V
Off-state gate voltage	$V_{\text{GS(off)}}$		-5	V

Table 5 Characteristic values

Parameter	Symbol	Note or test condition		Values			Unit
				Min.	Typ.	Max.	
Drain-source on-resistance	$R_{\text{DS(on)}}$	$I_{\text{D}} = 500 \text{ A}$	$V_{\text{GS}} = 15 \text{ V}, T_{vj} = 25 \text{ °C}$		3.8	4.8	mΩ
			$V_{\text{GS}} = 15 \text{ V}, T_{vj} = 125 \text{ °C}$		7.4	9.3	
			$V_{\text{GS}} = 15 \text{ V}, T_{vj} = 175 \text{ °C}$		10.6	13.3	
Gate threshold voltage	$V_{\text{GS(th)}}$	$I_{\text{D}} = 450 \text{ mA}, V_{\text{DS}} = V_{\text{GS}}, T_{vj} = 25 \text{ °C},$ (tested after 1ms pulse at $V_{\text{GS}} = +20 \text{ V}$)		3.45	4.3	5.55	V
Total gate charge	Q_{G}	$V_{\text{DD}} = 1800 \text{ V}, V_{\text{GS}} = -5/15 \text{ V}$			2.5		μC
Internal gate resistor	R_{Gint}	$T_{vj} = 25 \text{ °C}$			1.5		Ω
Input capacitance	C_{ISS}	$f = 100 \text{ kHz}, V_{\text{DS}} = 1800 \text{ V}, V_{\text{GS}} = 0 \text{ V}$	$T_{vj} = 25 \text{ °C}$		101		nF
Output capacitance	C_{OSS}	$f = 100 \text{ kHz}, V_{\text{DS}} = 1800 \text{ V}, V_{\text{GS}} = 0 \text{ V}$	$T_{vj} = 25 \text{ °C}$		1.38		nF
Reverse transfer capacitance	C_{RSS}	$f = 100 \text{ kHz}, V_{\text{DS}} = 1800 \text{ V}, V_{\text{GS}} = 0 \text{ V}$	$T_{vj} = 25 \text{ °C}$		0.058		nF
C_{OSS} stored energy	E_{OSS}	$V_{\text{DS}} = 1800 \text{ V}, V_{\text{GS}} = -5/15 \text{ V}, T_{vj} = 25 \text{ °C}$			2.9		mJ
Drain-source leakage current	I_{DSS}	$V_{\text{DS}} = 3300 \text{ V}, V_{\text{GS}} = -5 \text{ V}$	$T_{vj} = 25 \text{ °C}$			2000	μA
Gate-source leakage current	I_{GSS}	$V_{\text{DS}} = 0 \text{ V}, T_{vj} = 25 \text{ °C}$	$V_{\text{GS}} = 20 \text{ V}$			10000	nA

(table continues...)

Table 5 (continued) Characteristic values

Parameter	Symbol	Note or test condition	Values			Unit
			Min.	Typ.	Max.	
Turn-on delay time (inductive load)	$t_{d\ on}$	$I_D = 500\ A, R_{Gon} = 0.42\ \Omega,$ $V_{DD} = 1800\ V,$ $V_{GS} = -5/15\ V$	$T_{vj} = 25\ ^\circ C$	300		ns
			$T_{vj} = 125\ ^\circ C$	270		
			$T_{vj} = 175\ ^\circ C$	250		
Rise time (inductive load)	t_r	$I_D = 500\ A, R_{Gon} = 0.42\ \Omega,$ $V_{DD} = 1800\ V,$ $V_{GS} = -5/15\ V$	$T_{vj} = 25\ ^\circ C$	125		ns
			$T_{vj} = 125\ ^\circ C$	135		
			$T_{vj} = 175\ ^\circ C$	170		
Turn-off delay time (inductive load)	$t_{d\ off}$	$I_D = 500\ A, R_{Goff} = 1.2\ \Omega,$ $V_{DD} = 1800\ V,$ $V_{GS} = -5/15\ V$	$T_{vj} = 25\ ^\circ C$	240		ns
			$T_{vj} = 125\ ^\circ C$	260		
			$T_{vj} = 175\ ^\circ C$	280		
Fall time (inductive load)	t_f	$I_D = 500\ A, R_{Goff} = 1.2\ \Omega,$ $V_{DD} = 1800\ V,$ $V_{GS} = -5/15\ V$	$T_{vj} = 25\ ^\circ C$	60		ns
			$T_{vj} = 125\ ^\circ C$	60		
			$T_{vj} = 175\ ^\circ C$	60		
Turn-on time (resistive load)	t_{on_R}	$I_D = 500\ A, V_{DD} = 2000\ V,$ $V_{GS} = -5/15\ V,$ $R_{Gon} = 0.42\ \Omega$	$T_{vj} = 25\ ^\circ C$	0.26		μs
Turn-on energy loss per pulse	E_{on}	$I_D = 500\ A, V_{DD} = 1800\ V,$ $L_\sigma = 30\ nH, V_{GS} = -5/15\ V,$ $R_{Gon} = 0.42\ \Omega, di/dt = 8.3\ kA/\mu s$ ($T_{vj} = 175\ ^\circ C$)	$T_{vj} = 25\ ^\circ C$	85		mJ
			$T_{vj} = 125\ ^\circ C$	125		
			$T_{vj} = 175\ ^\circ C$	160		
Turn-off energy loss per pulse	E_{off}	$I_D = 500\ A, V_{DD} = 1800\ V,$ $L_\sigma = 30\ nH, V_{GS} = -5/15\ V,$ $R_{Goff} = 1.2\ \Omega, dv/dt = 23\ kV/\mu s$ ($T_{vj} = 175\ ^\circ C$)	$T_{vj} = 25\ ^\circ C$	40		mJ
			$T_{vj} = 125\ ^\circ C$	40		
			$T_{vj} = 175\ ^\circ C$	40		
SC data	I_{SC}	$V_{GS} = -5/15\ V,$ $V_{DD} = 2400\ V,$ $V_{DSmax} = V_{DSS} - L_{sDS} * di/dt,$ $R_G = 0.42\ \Omega$	$t_p = 3\ \mu s,$ $T_{vj} = 175\ ^\circ C$	5400		A
Thermal resistance, junction to case	R_{thJC}	per MOSFET			41.4	K/kW
Thermal resistance, case to heat sink	R_{thCH}	per MOSFET, $\lambda_{grease} = 1\ W/(m^*K)$		24.9		K/kW
Temperature under switching conditions	$T_{vj\ op}$		-40		175	$^\circ C$

3 Body diode (MOSFET)

Table 6 Maximum rated values

Parameter	Symbol	Note or test condition		Values	Unit
DC body diode forward current	I_{SD}	$T_{vj} = 175\text{ °C}$, $V_{GS} = -5\text{ V}$	$T_C = 80\text{ °C}$	500	A
I^2t - value	I^2t	$V_{DS} = 0\text{ V}$, $V_{GS} = -5\text{ V}$, $t_p = 10\text{ ms}$	$T_{vj} = 175\text{ °C}$	125	kA ² s

Table 7 Characteristic values

Parameter	Symbol	Note or test condition		Values			Unit
				Min.	Typ.	Max.	
Forward voltage	V_{SD}	$I_{SD} = 500\text{ A}$, $V_{GS} = -5\text{ V}$	$T_{vj} = 25\text{ °C}$		4.6	5.8	V
			$T_{vj} = 125\text{ °C}$		3.9	4.9	
			$T_{vj} = 175\text{ °C}$		3.6	4.5	
Reverse recovery energy	E_{rec}	$I_{SD} = 500\text{ A}$, $di_s/dt = 8.3\text{ kA}/\mu\text{s}$ ($T_{vj} = 175\text{ °C}$), $V_{DD} = 1800\text{ V}$, $V_{GS} = -5\text{ V}$	$T_{vj} = 25\text{ °C}$		13		mJ
			$T_{vj} = 125\text{ °C}$		27		
			$T_{vj} = 175\text{ °C}$		40		

4 NTC-Thermistor

Table 8 Characteristic values

Parameter	Symbol	Note or test condition	Values			Unit
			Min.	Typ.	Max.	
Rated resistance	R_{25}	$T_{NTC} = 25\text{ °C}$		5		kΩ
Deviation of R_{100}	$\Delta R/R$	$T_{NTC} = 100\text{ °C}$, $R_{100} = 493\text{ Ω}$	-5		5	%
Power dissipation	P_{25}	$T_{NTC} = 25\text{ °C}$			20	mW
B-value	$B_{25/50}$	$R_2 = R_{25} \exp[B_{25/50}(1/T_2 - 1/(298,15\text{ K}))]$		3375		K
B-value	$B_{25/80}$	$R_2 = R_{25} \exp[B_{25/80}(1/T_2 - 1/(298,15\text{ K}))]$		3411		K
B-value	$B_{25/100}$	$R_2 = R_{25} \exp[B_{25/100}(1/T_2 - 1/(298,15\text{ K}))]$		3433		K

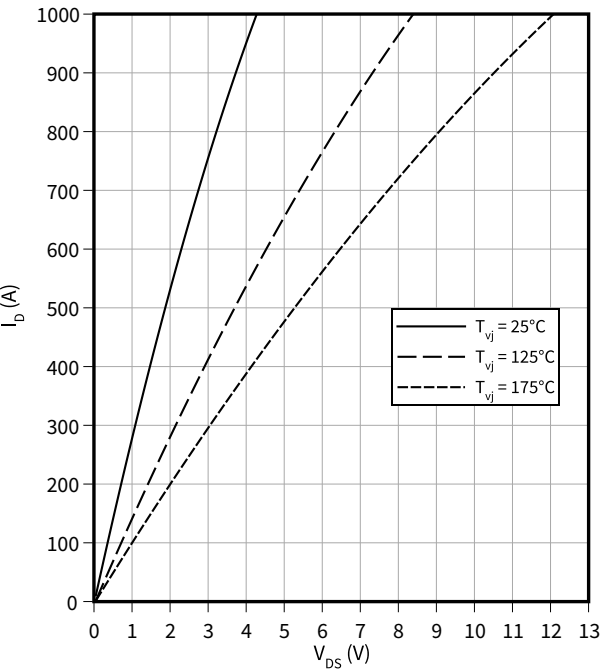
Note: For an analytical description of the NTC characteristics please refer to AN2009-10, chapter 4.

5 Characteristics diagrams

Output characteristic (typical), MOSFET

$I_D = f(V_{DS})$

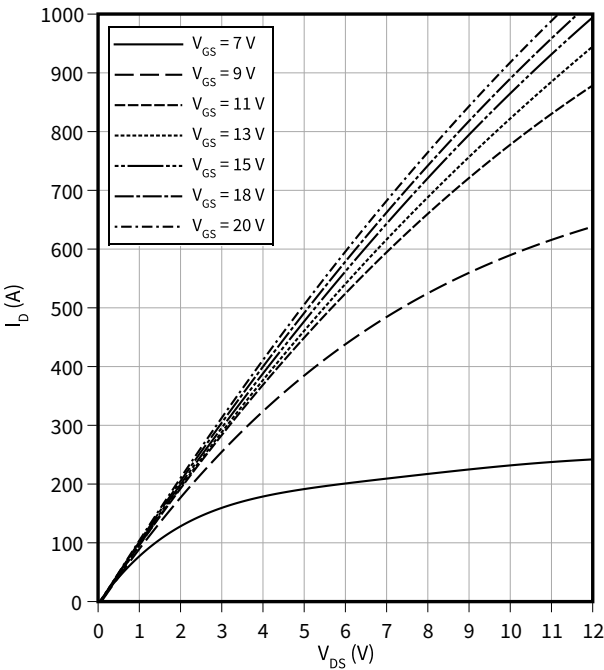
$V_{GS} = 15\text{ V}$



Output characteristic field (typical), MOSFET

$I_D = f(V_{DS})$

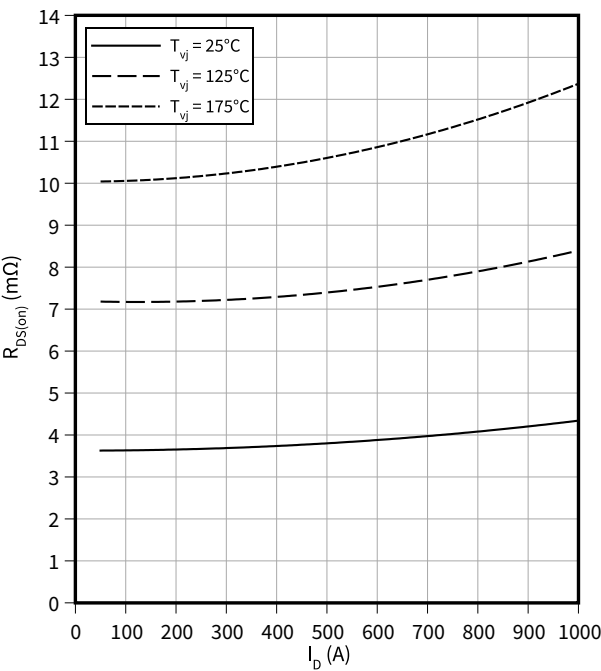
$T_{vj} = 175^\circ\text{C}$



Drain source on-resistance (typical), MOSFET

$R_{DS(on)} = f(I_D)$

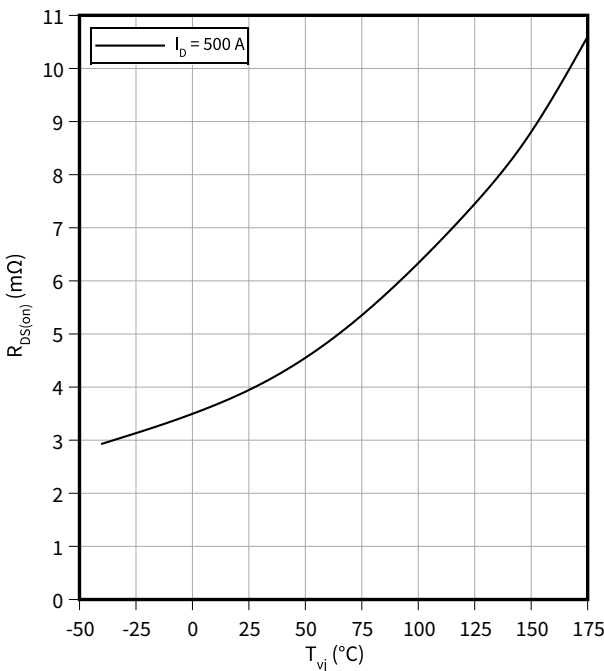
$V_{GS} = 15\text{ V}$



Drain source on-resistance (typical), MOSFET

$R_{DS(on)} = f(T_{vj})$

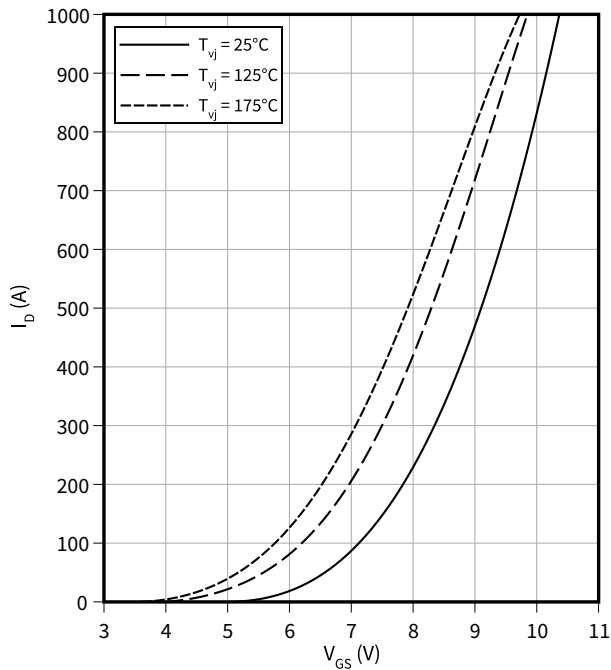
$V_{GS} = 15\text{ V}$



5 Characteristics diagrams

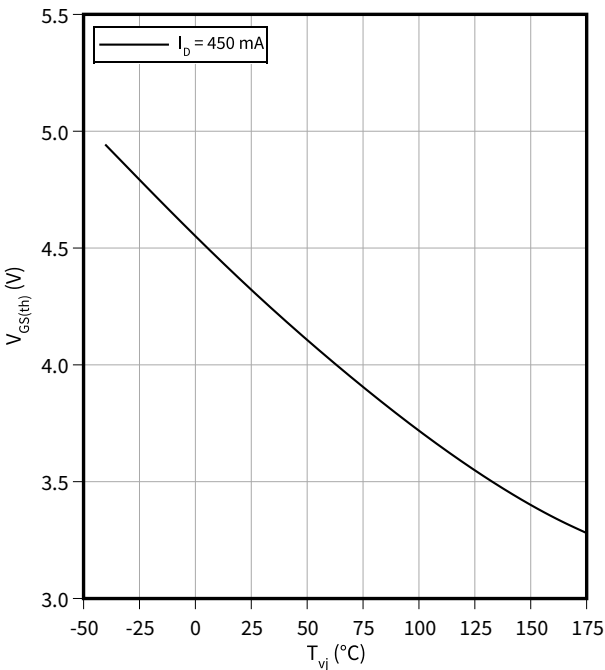
Transfer characteristic (typical), MOSFET

$I_D = f(V_{GS})$
 $V_{DS} = 20\text{ V}$



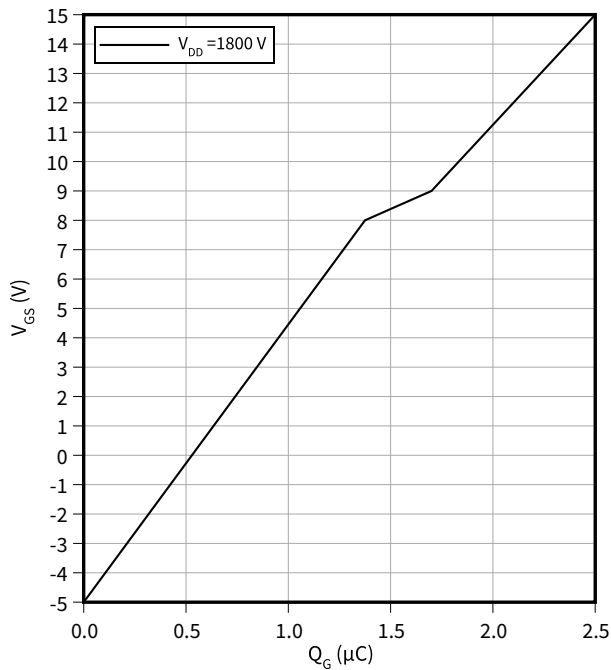
Gate-source threshold voltage (typical), MOSFET

$V_{GS(th)} = f(T_{vj})$
 $V_{GS} = V_{DS}$



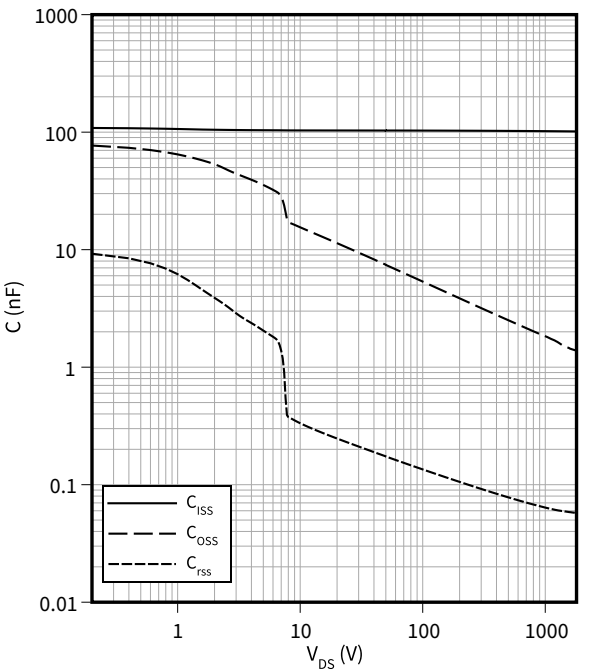
Gate charge characteristic (typical), MOSFET

$V_{GS} = f(Q_G)$
 $I_D = 500\text{ A}, T_{vj} = 25^\circ\text{C}$



Capacity characteristic (typical), MOSFET

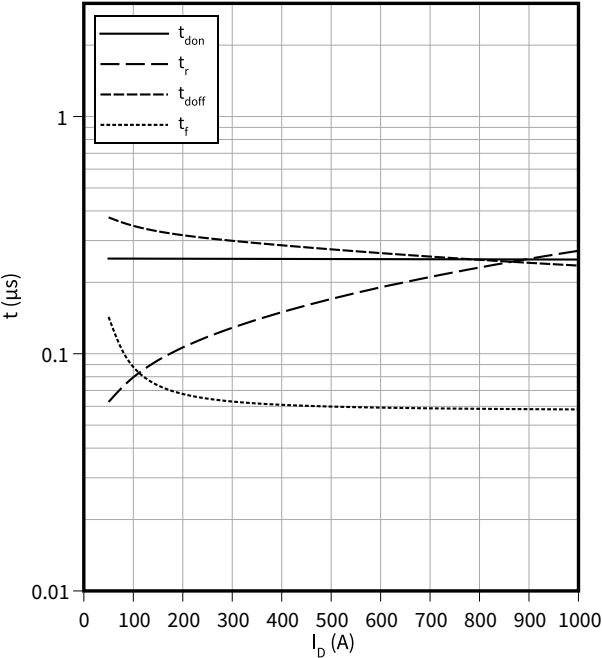
$C = f(V_{DS})$
 $f = 100\text{ kHz}, T_{vj} = 25^\circ\text{C}, V_{GS} = 0\text{ V}$



5 Characteristics diagrams

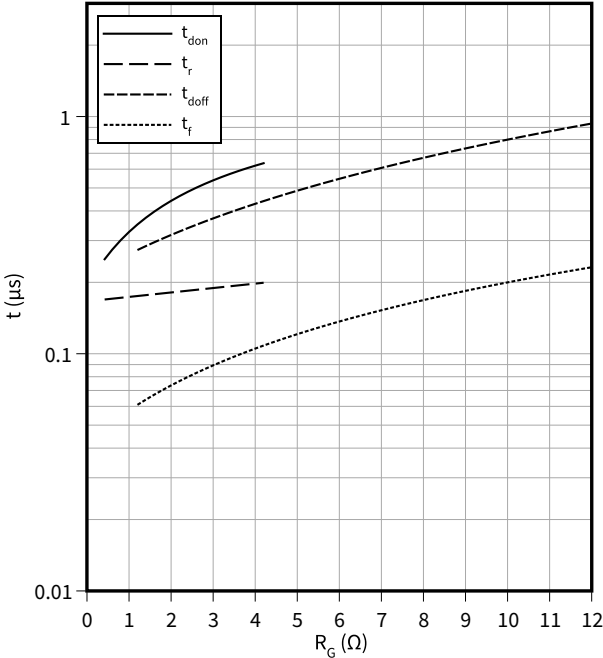
Switching times (typical), MOSFET

$t = f(I_D)$
 $R_{Goff} = 1.2\ \Omega$, $R_{Gon} = 0.42\ \Omega$, $V_{DD} = 1800\text{ V}$, $T_{vj} = 175\text{ }^\circ\text{C}$, $V_{GS} = -5/15\text{ V}$



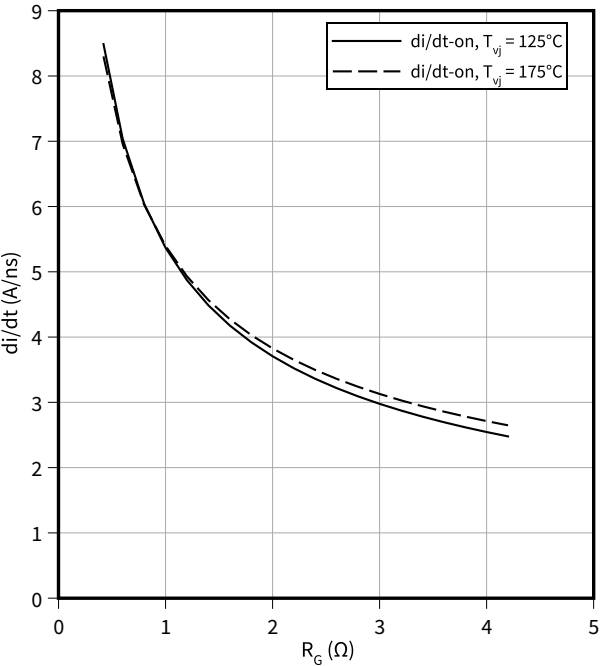
Switching times (typical), MOSFET

$t = f(R_G)$
 $V_{DD} = 1800\text{ V}$, $I_D = 500\text{ A}$, $T_{vj} = 175\text{ }^\circ\text{C}$, $V_{GS} = -5/15\text{ V}$



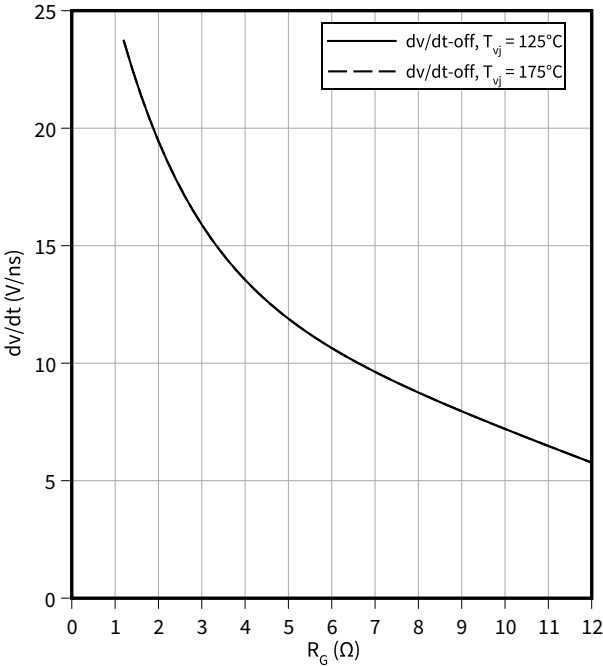
Current slope (typical), MOSFET

$di/dt = f(R_G)$
 $V_{DD} = 1800\text{ V}$, $I_D = 500\text{ A}$, $V_{GS} = -5/15\text{ V}$



Voltage slope (typical), MOSFET

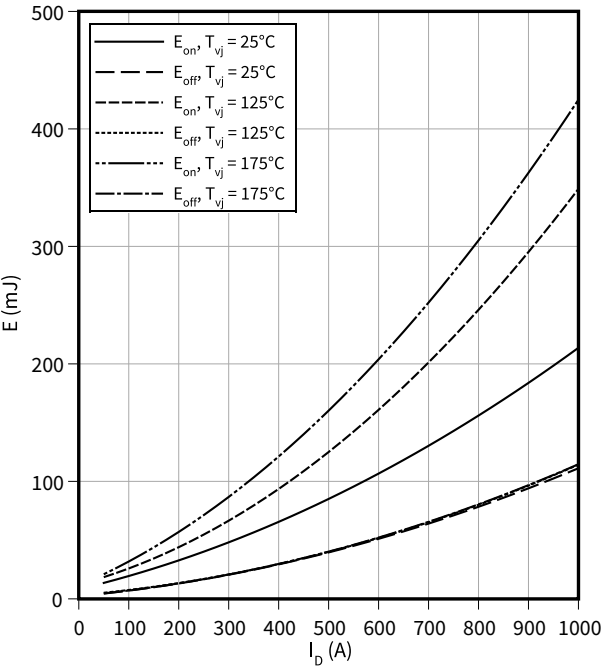
$dv/dt = f(R_G)$
 $V_{DD} = 1800\text{ V}$, $I_D = 500\text{ A}$, $V_{GS} = -5/15\text{ V}$



5 Characteristics diagrams

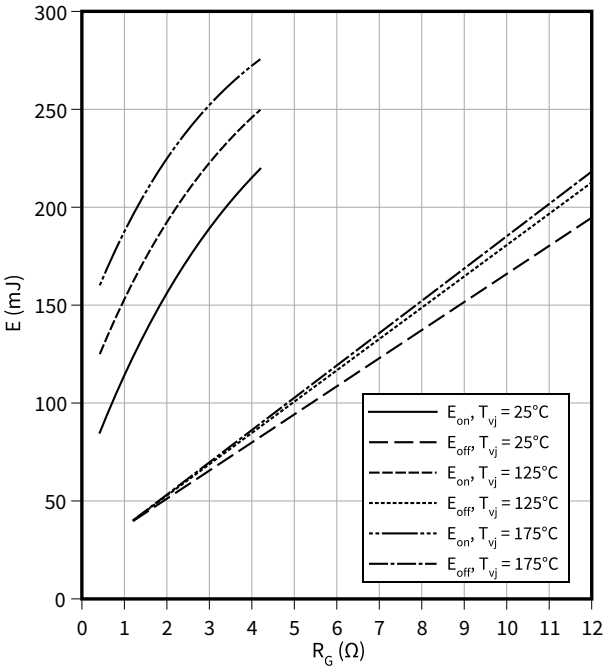
Switching losses (typical), MOSFET

$E = f(I_D)$
 $R_{Goff} = 1.2\ \Omega$, $R_{Gon} = 0.42\ \Omega$, $V_{DD} = 1800\text{ V}$, $V_{GS} = -5/15\text{ V}$



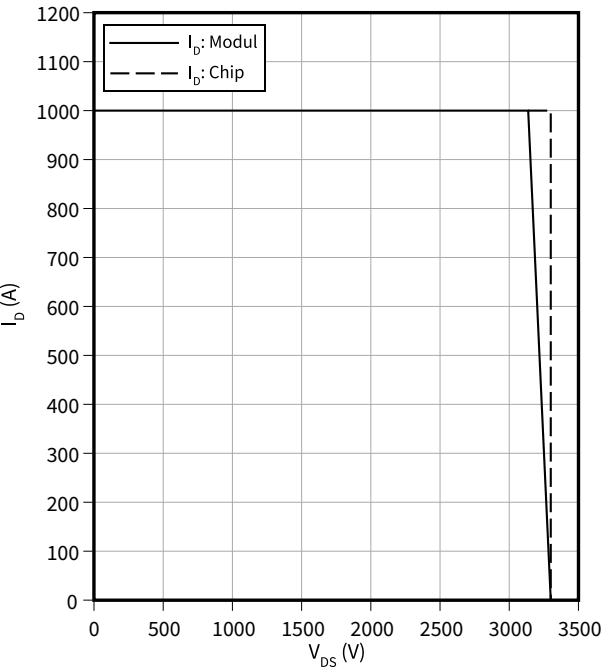
Switching losses (typical), MOSFET

$E = f(R_G)$
 $V_{DD} = 1800\text{ V}$, $I_D = 500\text{ A}$, $V_{GS} = -5/15\text{ V}$



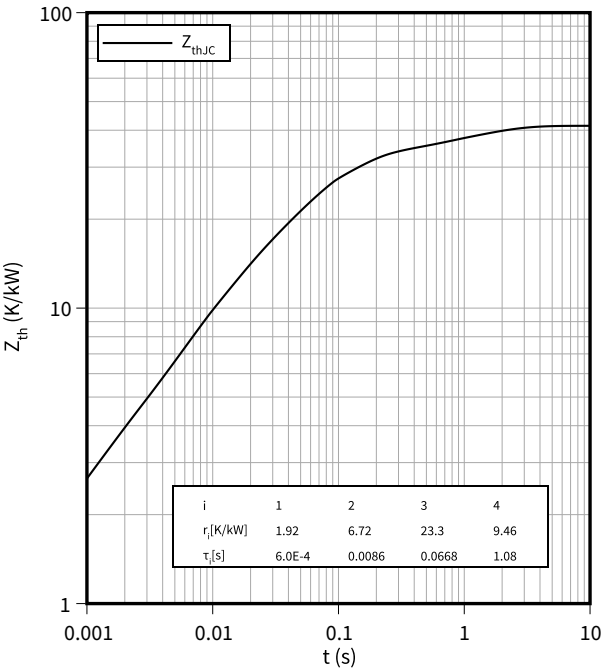
Reverse bias safe operating area (RBSOA), MOSFET

$I_D = f(V_{DS})$
 $R_{Goff} = 1.2\ \Omega$, $T_{vj} = 175\text{ °C}$, $V_{GS} = -5/15\text{ V}$



Transient thermal impedance, MOSFET

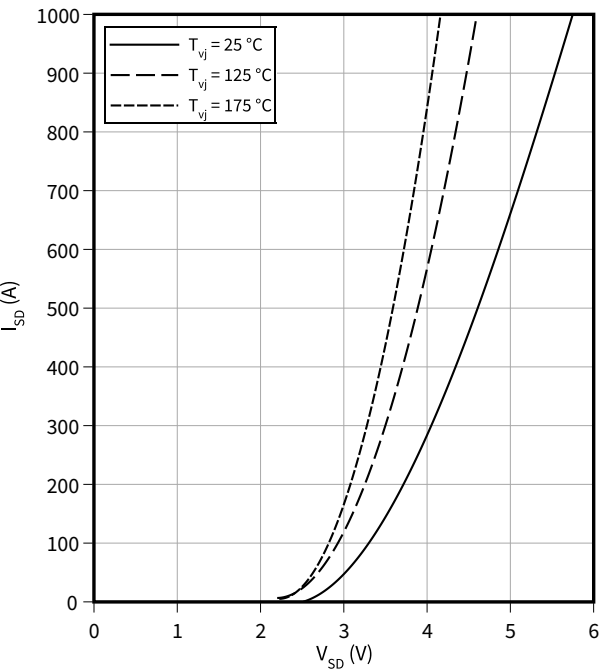
$Z_{th} = f(t)$



5 Characteristics diagrams

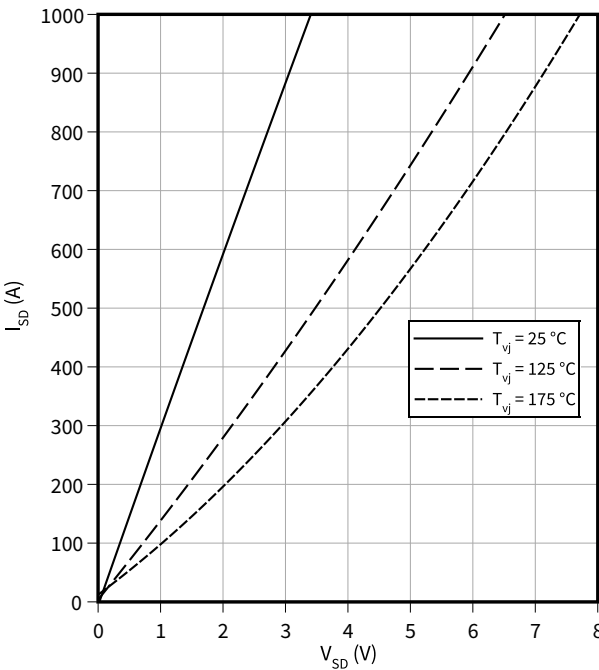
Forward characteristic body diode (typical), MOSFET

$I_{SD} = f(V_{SD})$
 $V_{GS} = -5\text{ V}$



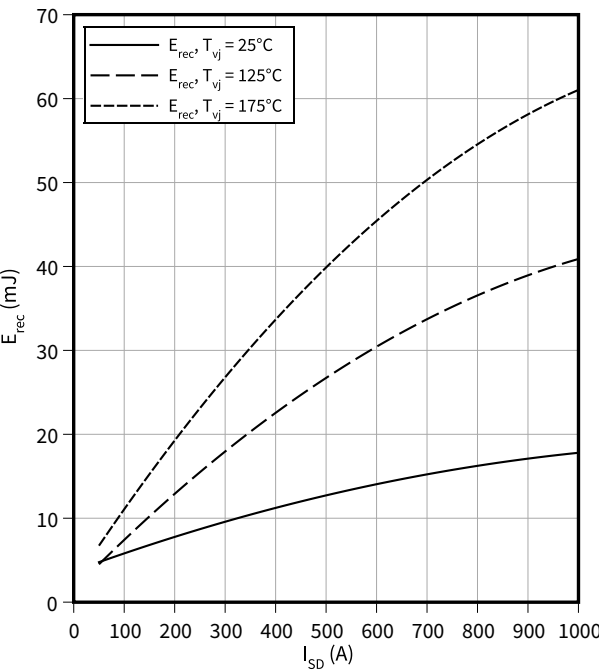
Forward characteristic body diode (typical), MOSFET

$I_{SD} = f(V_{SD})$
 $V_{GS} = 15\text{ V}$



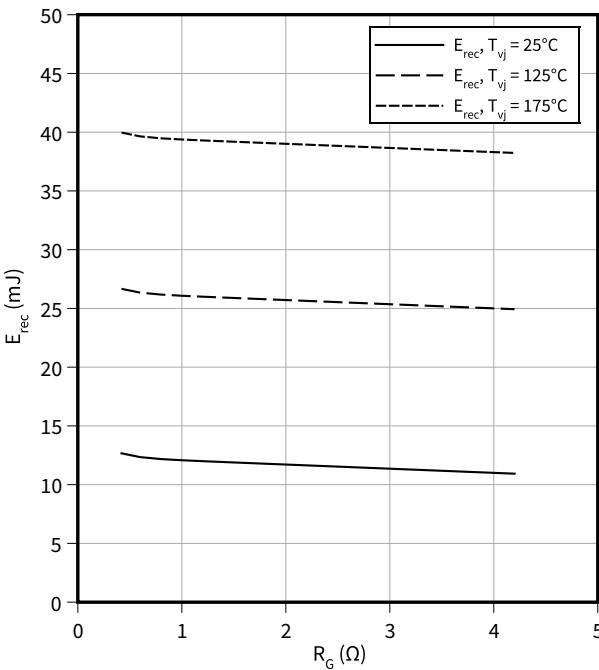
Switching losses body diode (typical), MOSFET

$E_{rec} = f(I_{SD})$
 $R_{Gon} = 0.42\ \Omega$, $V_{DD} = 1800\text{ V}$



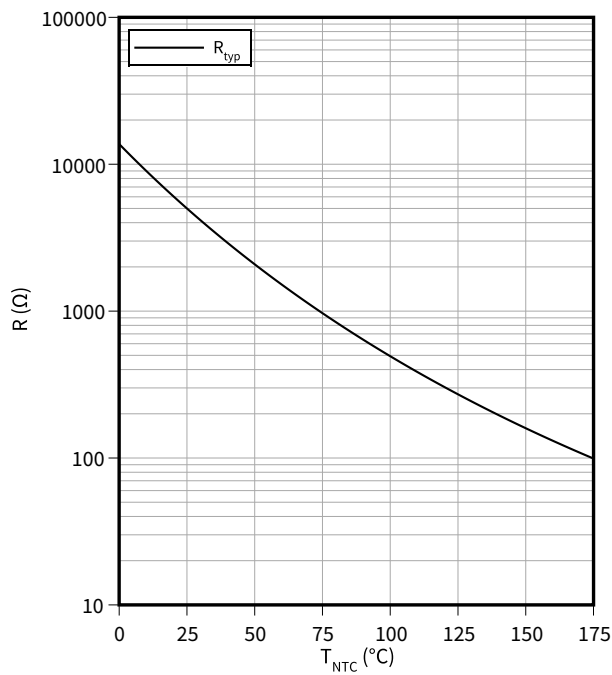
Switching losses body diode (typical), MOSFET

$E_{rec} = f(R_G)$
 $V_{DD} = 1800\text{ V}$, $I_{SD} = 500\text{ A}$



Temperature characteristic (typical), NTC-Thermistor

$R = f(T_{NTC})$



6 Circuit diagram

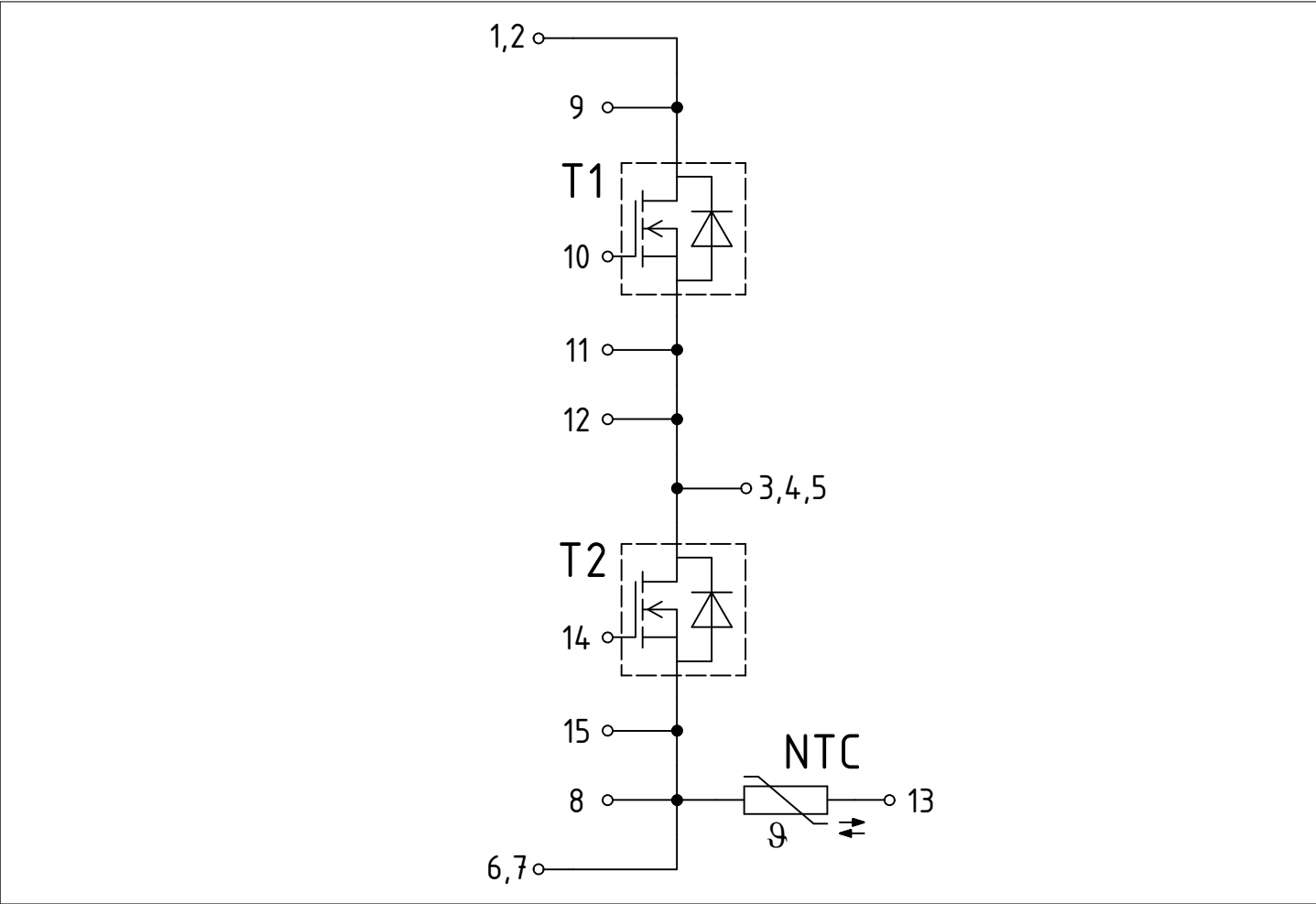


Figure 1

7 Package outlines

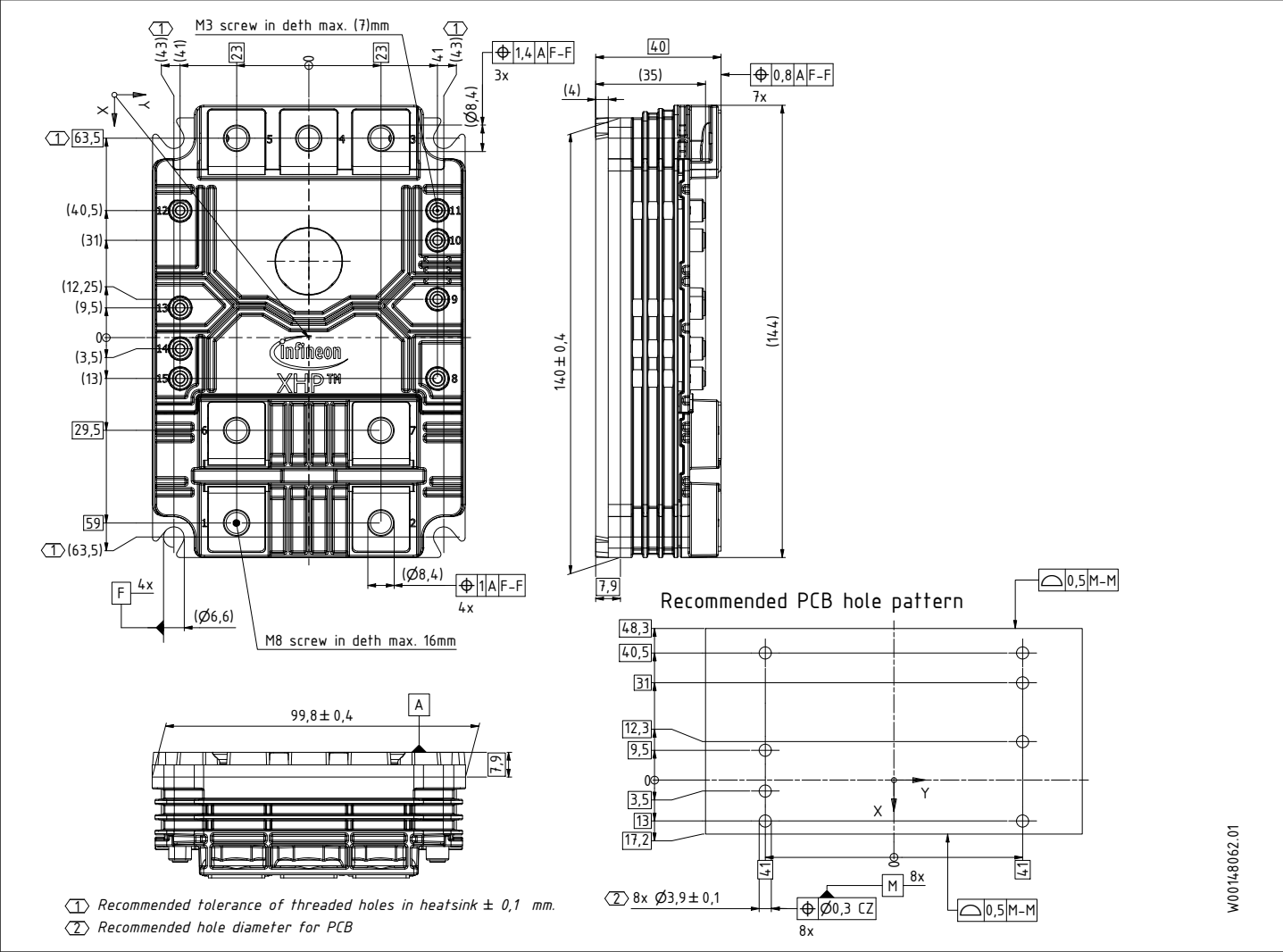


Figure 2

8 Module label code



Module label code			
Code format	Data Matrix		Barcode Code128
Encoding	ASCII text		Code Set A
Symbol size	16x16		23 digits
Standard	IEC24720 and IEC16022		IEC8859-1
Code content	<i>Content</i>	<i>Digit</i>	<i>Example</i>
	Module serial number	1 – 5	71549
	Module material number	6 - 11	142846
	Production order number	12 - 19	55054991
	Date code (production year)	20 – 21	15
	Date code (production week)	22 – 23	30
Example			
	 71549142846550549911530	 71549142846550549911530	

Figure 3



Revision history

Revision history

Document revision	Date of release	Description of changes
1.00	2024-07-05	Initial version

Trademarks

All referenced product or service names and trademarks are the property of their respective owners.

Edition 2024-07-05

Published by

Infineon Technologies AG
81726 Munich, Germany

© 2024 Infineon Technologies AG
All Rights Reserved.

Do you have a question about any
aspect of this document?

Email: erratum@infineon.com

Document reference
IFX-ABK369-001

Important notice

The information given in this document shall in no event be regarded as a guarantee of conditions or characteristics ("Beschaffenhheitsgarantie").

With respect to any examples, hints or any typical values stated herein and/or any information regarding the application of the product, Infineon Technologies hereby disclaims any and all warranties and liabilities of any kind, including without limitation warranties of non-infringement of intellectual property rights of any third party.

In addition, any information given in this document is subject to customer's compliance with its obligations stated in this document and any applicable legal requirements, norms and standards concerning customer's products and any use of the product of Infineon Technologies in customer's applications.

The data contained in this document is exclusively intended for technically trained staff. It is the responsibility of customer's technical departments to evaluate the suitability of the product for the intended application and the completeness of the product information given in this document with respect to such application.

Warnings

Due to technical requirements products may contain dangerous substances. For information on the types in question please contact your nearest Infineon Technologies office.

Except as otherwise explicitly approved by Infineon Technologies in a written document signed by authorized representatives of Infineon Technologies, Infineon Technologies' products may not be used in any applications where a failure of the product or any consequences of the use thereof can reasonably be expected to result in personal injury.